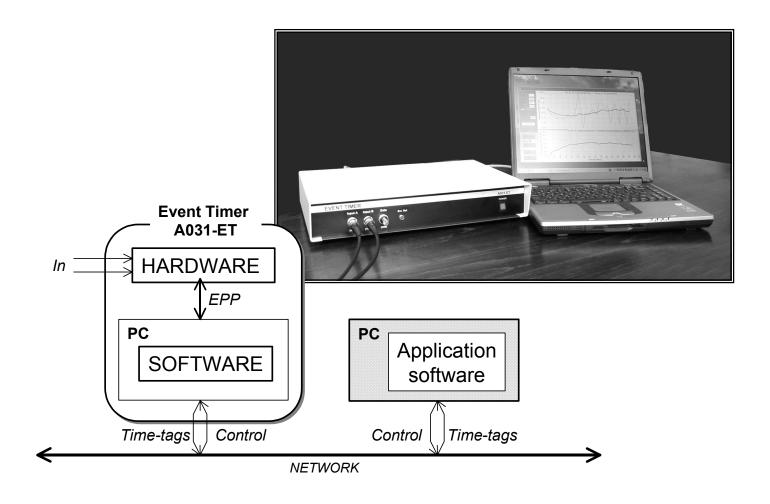
# **Evaluation of Event Timer A031-ET performance**

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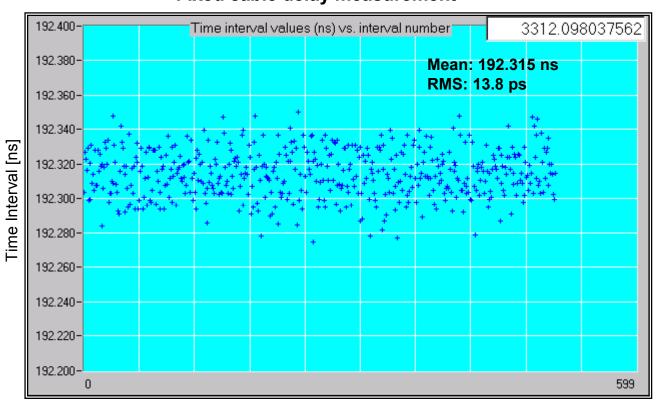


Inputs: NIM pulses, ~5ns/V falling edge

500 readings

Repetition rate: 10 Hz

# Fixed cable delay measurement

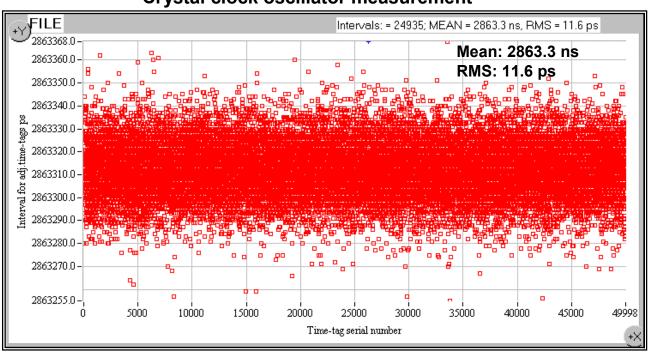


Input: low-jittered NIM pulses, ~2ns/V falling edge

24 935 readings

Repetition rate: 3.8 KHz

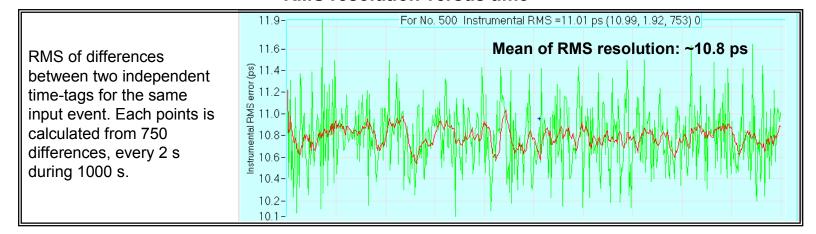
# **Crystal clock oscillator measurement**



As a special feature, the A031-ET can provide two independent time-tags for the same event from some part of all input events. This is a basis for evaluation of A031-ET

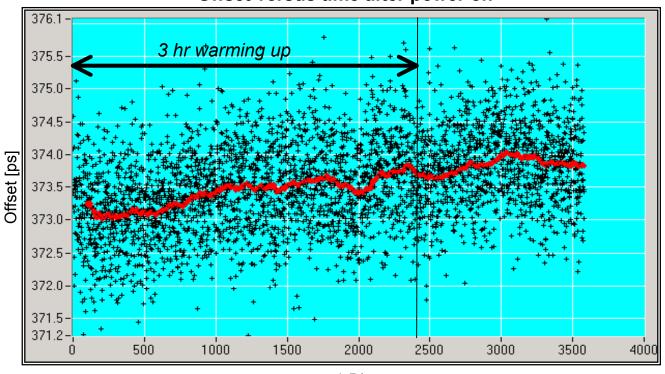
true resolution using test signals with undefined instability.

#### RMS resolution versus time



Ambient temperature 21  $\pm$ 0.5  $^{0}$ C Temperature inside the case rises from 20 to 40  $^{0}$ C Test duration: 4.5 hr Each point is mean of 900 readings

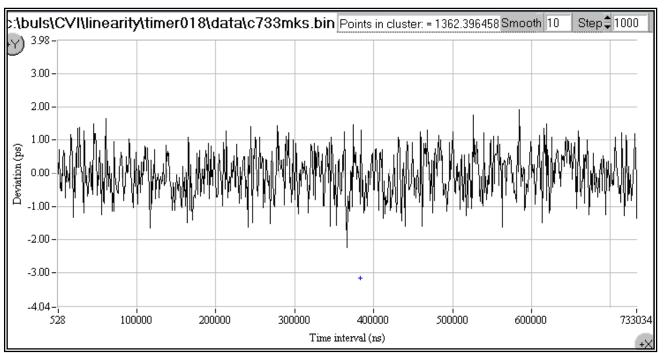
Offset versus time after power on



x 4.51 s

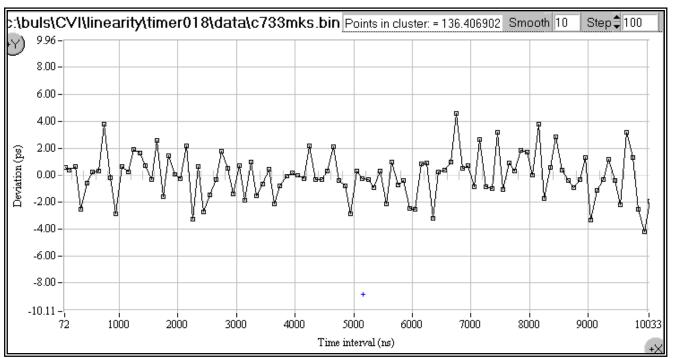
Evaluation error (RMS): ~0.45 ps

Non-linearity error versus time interval (0.5 to 733  $\mu$ s range) in combination with evaluation errors



Evaluation error (RMS): ~1.6 ps

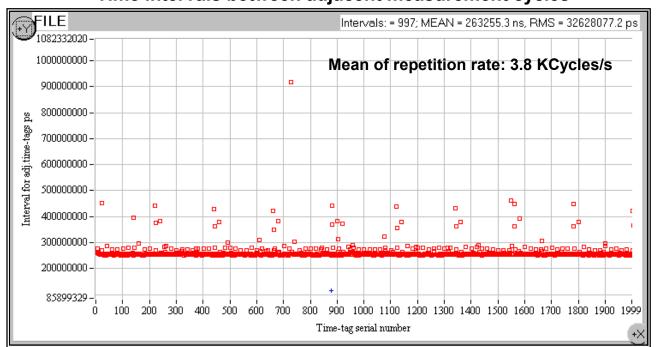
# Non-linearity error versus time interval (70 ns to 10 $\mu$ s range) in combination with evaluation errors



The A031-ET measures 2.8  $\mu s$  time interval in each cycle under internal triggering

Used PC: Pentium IV 1.8 GHz

# Time intervals between adjacent measurement cycles



LSB resolution1 ps

• RMS resolution (Jitter)  $10.8 \pm 0.6$  ps

Non-linearity error less than ±1 ps

Temporal stability better than ±0.5 ps/hr

• Temperature drift less than 0.1 ps/ °C

Maximum repetition rate:

mean - 3.6 KCycles/s

assured - 1 KCycles/s